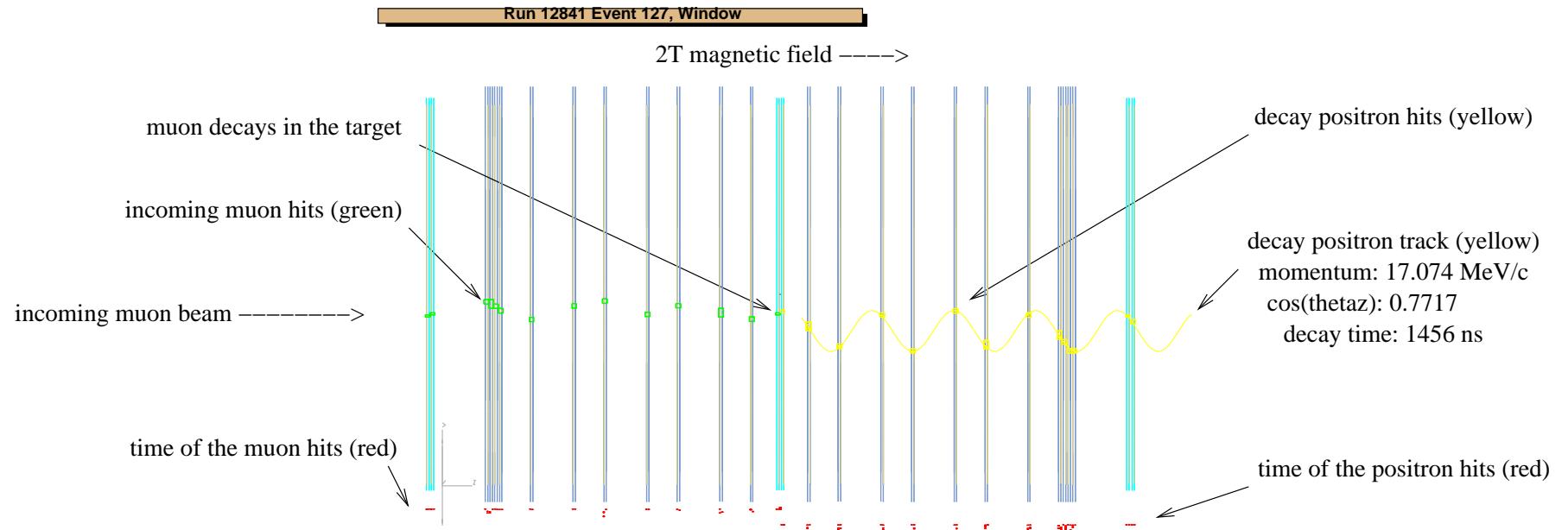


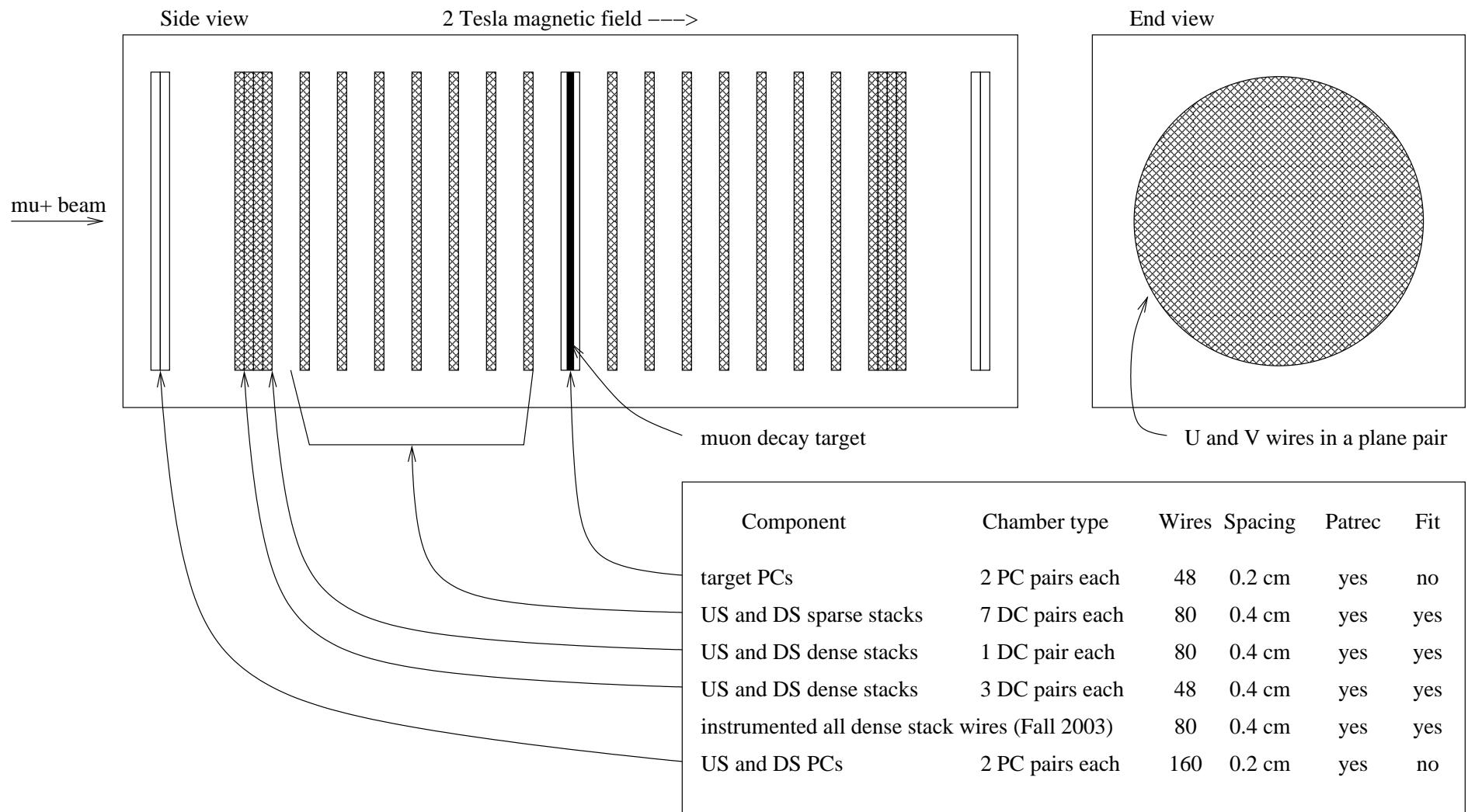
TWIST Data analysis techniques

Konstantin Olchanski, TRIUMF, June 2004



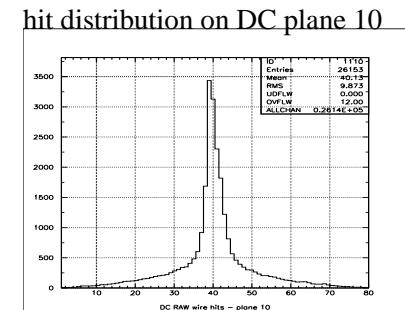
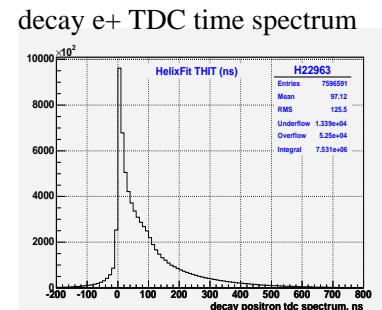
- Plan:
- Above: typical muon decay event
 - describe TWIST detector
 - discuss TWIST event reconstruction:
 - pattern recognition
 - wire-centers track fitting with narrow-windows and kinks
 - drift-time track fitting with kinks
 - energy scale calibrations and energy loss correction
 - extraction of Michel parameters
 - estimation of systematic errors
 - how it is all done on the WestGrid/UBC 1000-CPU Linux cluster

Tracking components of the TWIST spectrometer

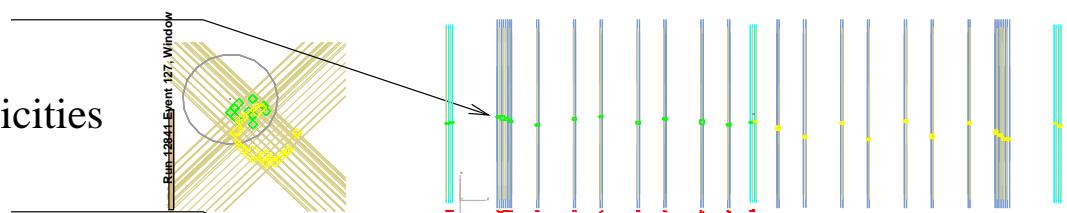


Track reconstruction sequence

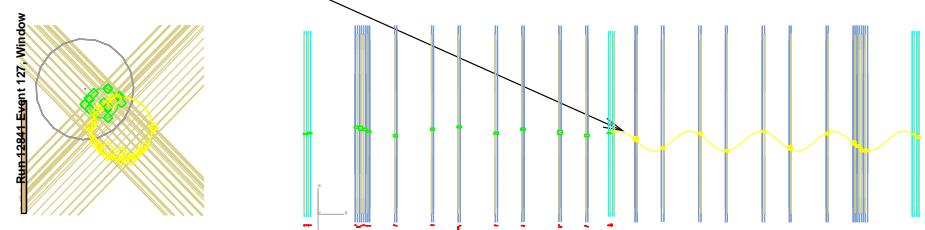
- start with raw TDC hits
- remove cross talk hits
- resolve mu+ and e+ hits in time
- assemble U and V hits into 3D clusters
- particle ID using ADCs and plane multiplicities
- find tracks, resolve charge, helix period
- "narrow windows" wire–centers fit with kinks
- resolve L–R ambiguities, measure decay time
- final drift fit with kinks



3D clusters for mu+ hits (green) and e+ hits (yellow)
Run 12841 Event 127, Window



pattern recognition found the e+ track (yellow)
Run 12841 Event 127, Window



Six track fit parameters: decay time, helix center u and v, radius (pt), 1/period (1/pl) and mean phase

Main methods used:

- Gauss–Newton method for non–linear Least–Squares (Numerical Recipes)
- wire–centers reconstruction using "narrow windows" (F.James, CERN, 1982)
- "kink method" for handling multiple scattering (G.Lutz, NIMA, 1988)

The Gauss–Newton method for non–linear least squares and the kink method

$$(\chi)^2 = \sum \frac{(\text{trk}(\text{par}) - \text{hit})^2}{\sigma^2} \xrightarrow{\text{par}} \min$$

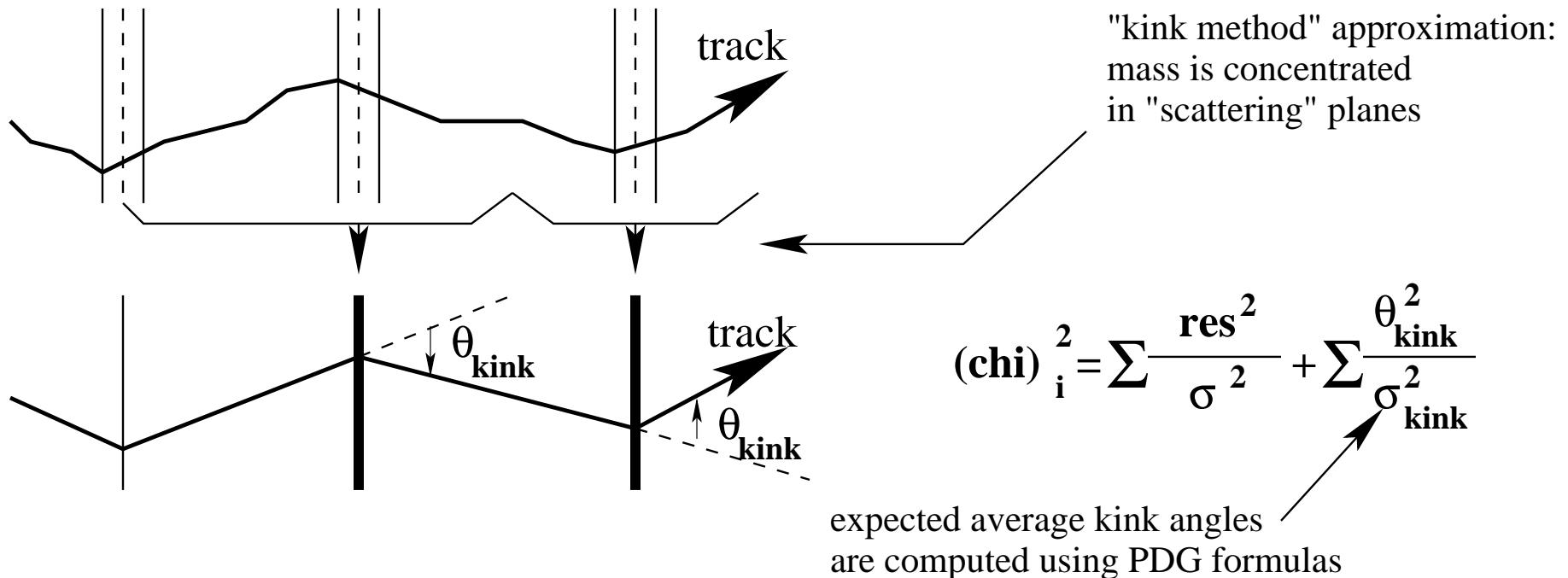
Linearize: $\text{trk}(\text{par}(n+1)) = \text{trk}(\text{par}(n)) + \frac{d\text{trk}/d\text{par}}{} * (\text{par}(n+1) - \text{par}(n))$

Iterate: **par(0) = from pattern recognition**

$$\text{par}(n+1) = \text{par}(n) + A * (\text{trk}(\text{par}(n)) - \text{hits})$$

gradients are
computed numerically

Account for scattering by adding kinks (G. Lutz, NIMA, 1988):



$$(\chi)^2_i = \sum \frac{\text{res}^2}{\sigma^2}$$

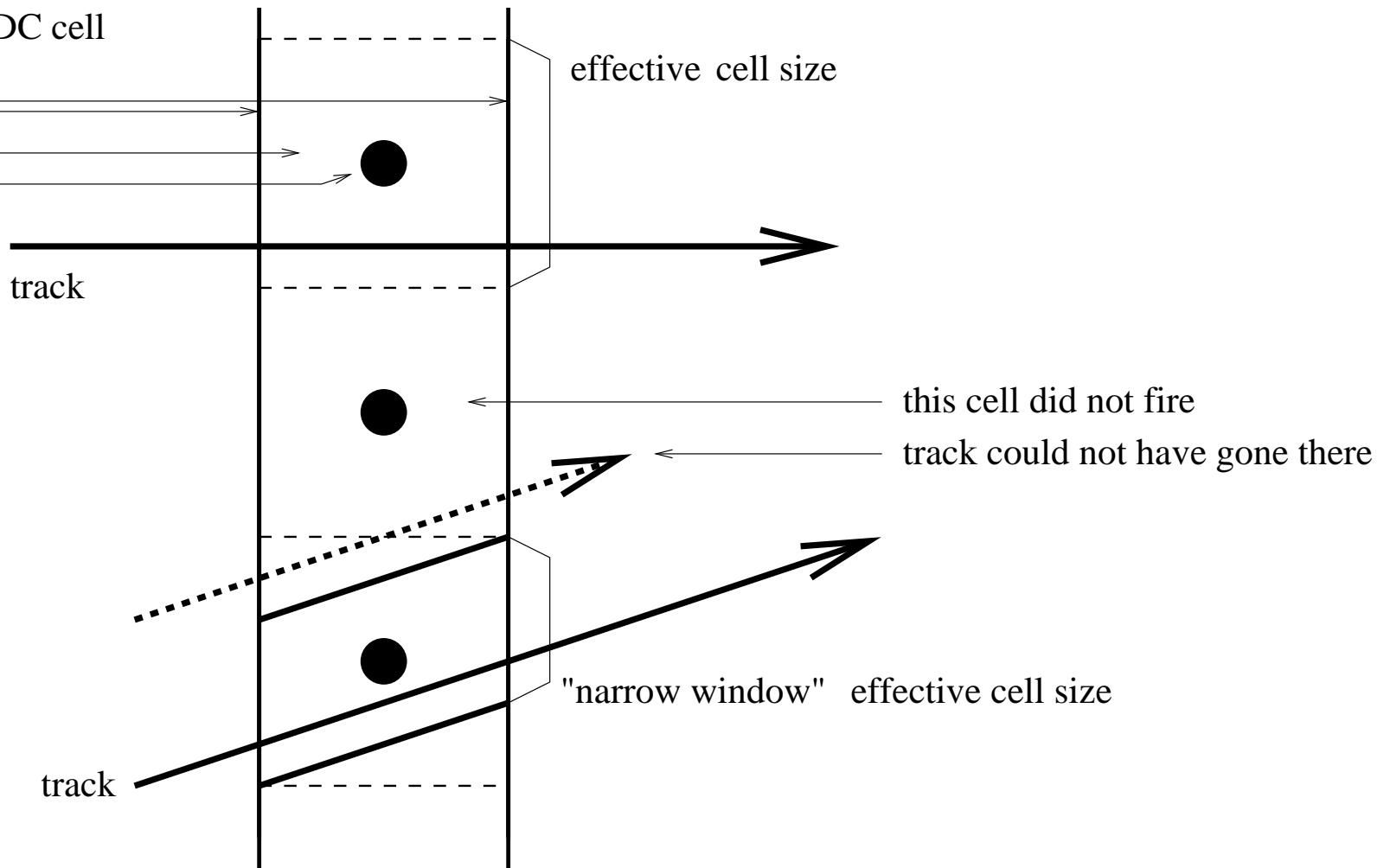
(effective cell width)/sqrt(12)

Anatomy of TWIST DC cell

Cathode Foils

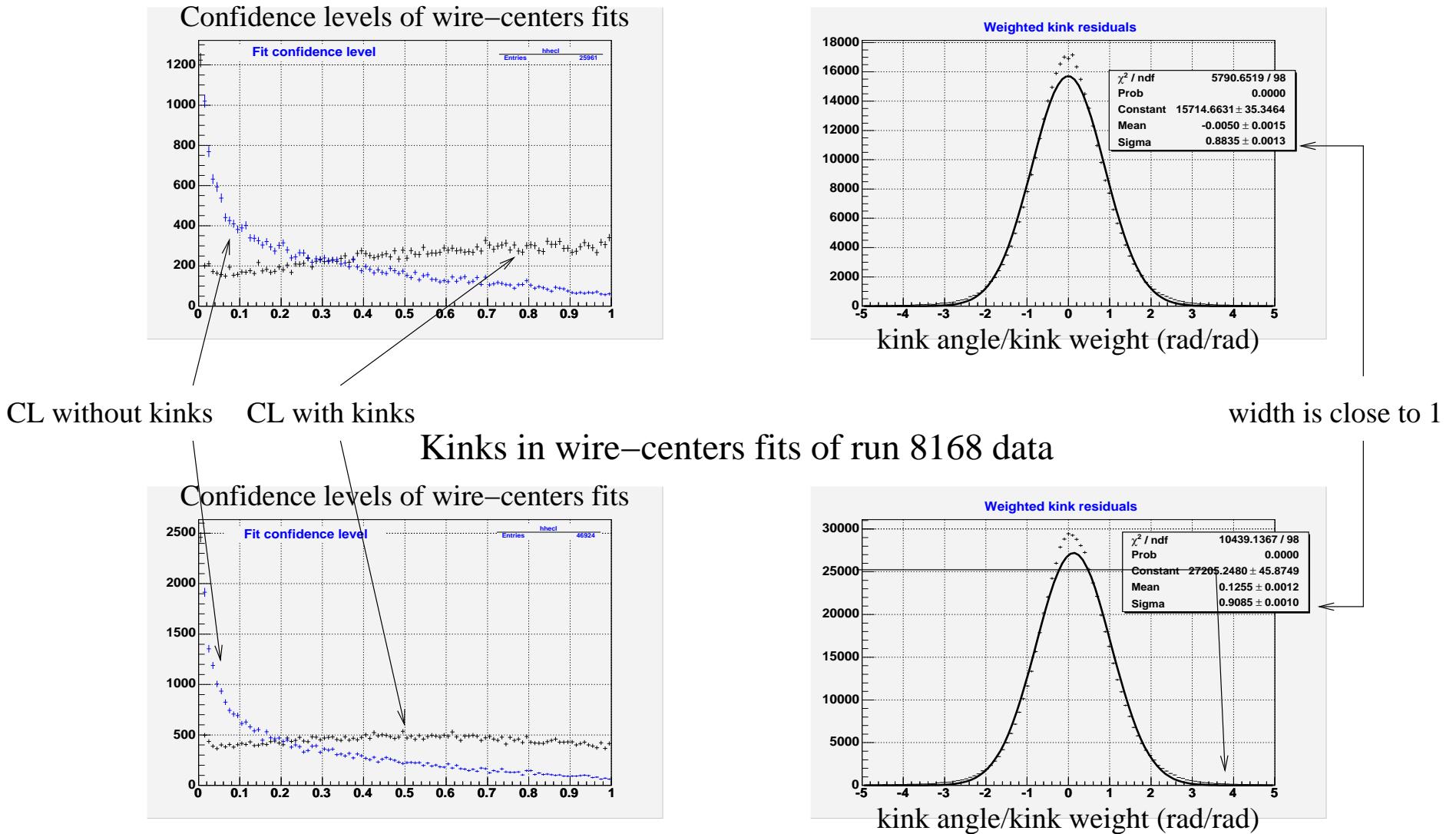
DME gas

Anode Wire



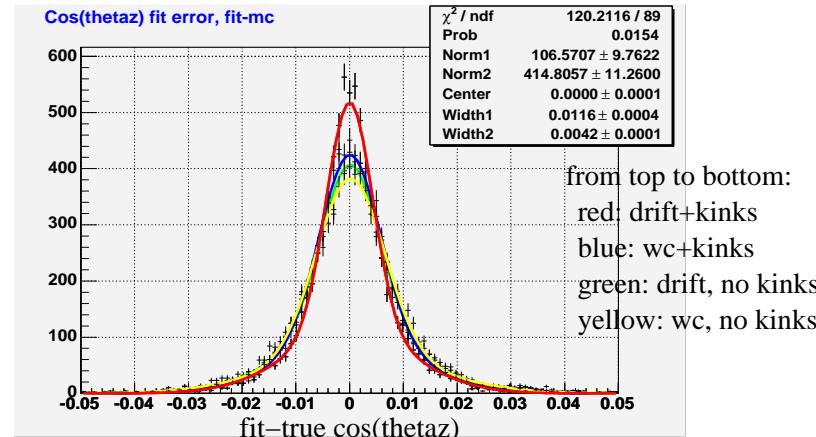
Using the "kink" method to handle multiple scattering

Kinks in wire-centers fits of geant3 data

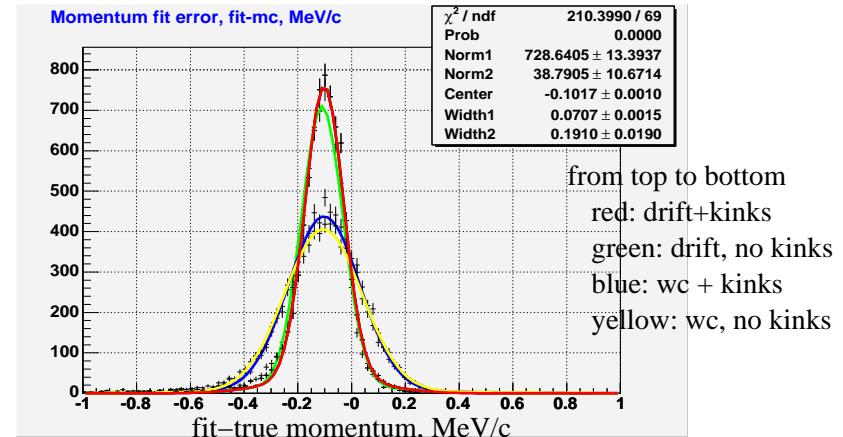


Resolution of helix fits

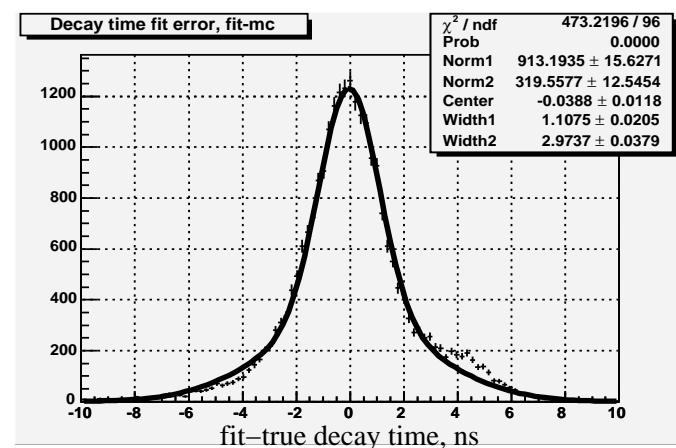
$\cos(\text{theta}z)$ resolution



Momentum resolution



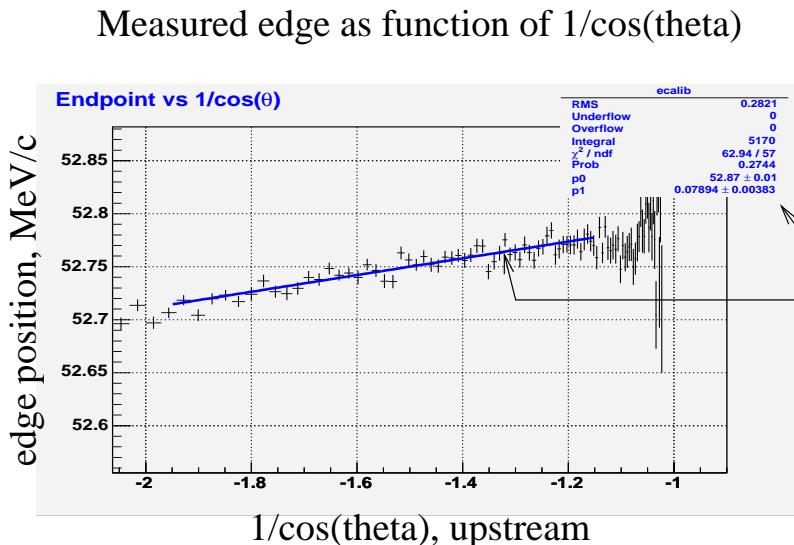
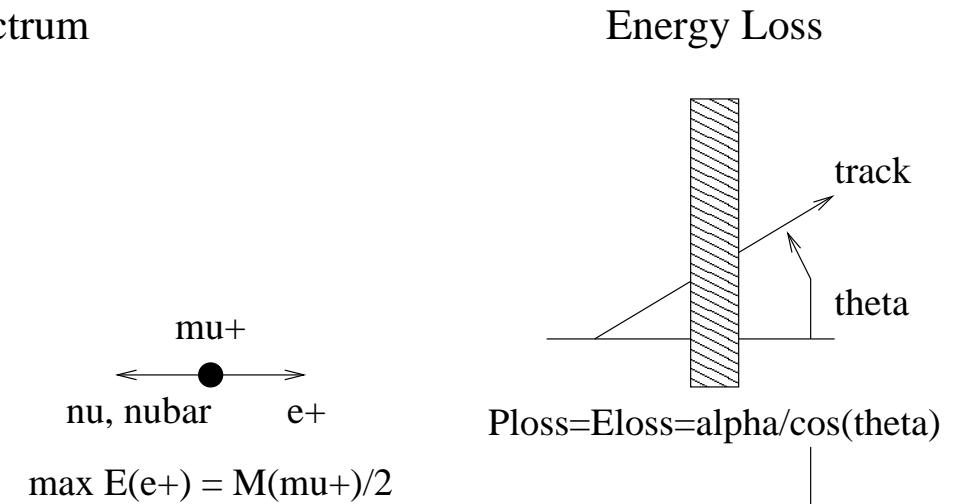
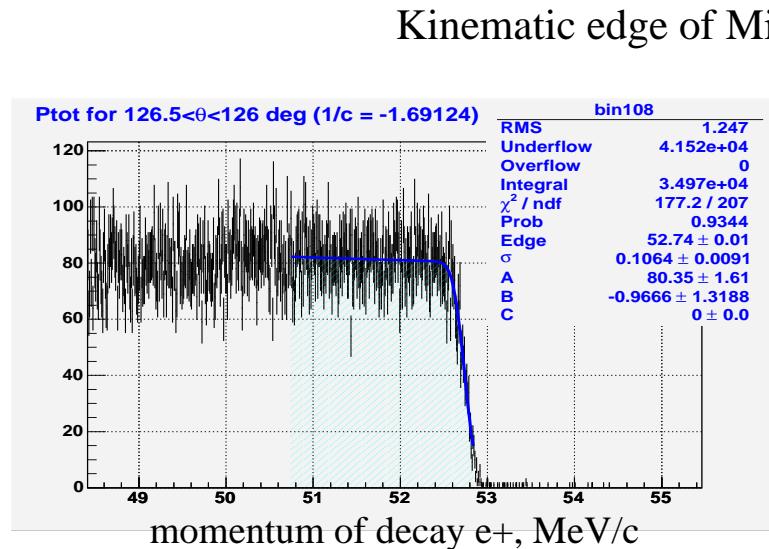
Decay time resolution



Resolution of drift fits with kinks:

- $\cos(\text{theta}z)$: 0.0057 (includes scattering in the target)
- momentum: 0.077 MeV/c
- shift in momentum is due to energy loss
corrected later by energy scale calibration
- decay time: 1.5 ns

Calibration and correction of energy scale and energy loss.



Calibration and correction:

Model:

$$P_{\text{measured}} = P_{\text{true}} * B/B_{\text{true}} - P_{\text{loss}}$$

At edge:

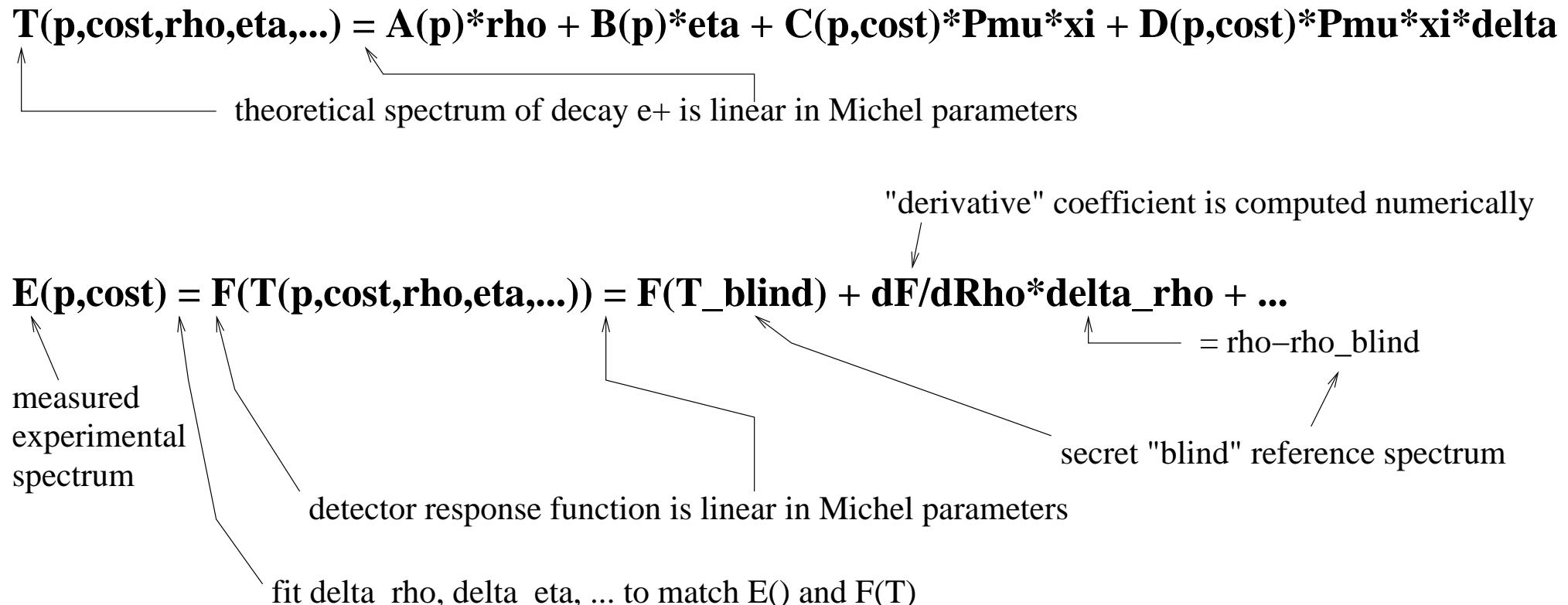
$$P_{\text{edge}} = P_{\text{true edge}} * B/B_{\text{true}} - \alpha / \cos(\theta)$$

straight-line fit yields B/B_{true} and α

Energy scale and energy loss correction:

$$P_{\text{corrected}} = P_{\text{measured}} * B_{\text{true}}/B + \alpha / \cos(\theta)$$

Extraction of Michel parameters



Above linear expansion yields $\delta_\rho, \delta_\eta, \dots$ as linear function of $E(), F(T_{\text{blind}}), dF/d\rho, \dots$

Blinding:

- 1) use secret $T_{\text{blind}}(\rho_{\text{blind}}, \dots)$ with Michel parameters offset from Standard Model values
- 2) measure $\delta_\rho, \delta_\eta, \dots$ as above
- 3) "open the box", compute and publish: $\rho = \rho_{\text{blind}} + \delta_\rho, \dots$

Estimation of systematic errors on Michel parameters

$$E(p, cost) = F(T(p, cost, rho, eta, \dots))$$

↑
experimental
spectrum

↑
theoretical spectrum

↑
how well do we need to know the detector response function?

how well do we need to know the experimental spectrum? (i.e. variations between data runs)

Quantify the uncertainty in $E()$ and $F()$ in terms of variations in (blinded) Michel parameters (δ_ρ , ...)

- 1) compare data with simulations (what is the variation between data sets?)

$$E = E(T_{\text{blind}}) + dF/d\rho * \delta_\rho + \dots \quad \longrightarrow \quad \rho_{\text{true}} = \rho_{\text{blind}} + \delta_\rho, \dots$$

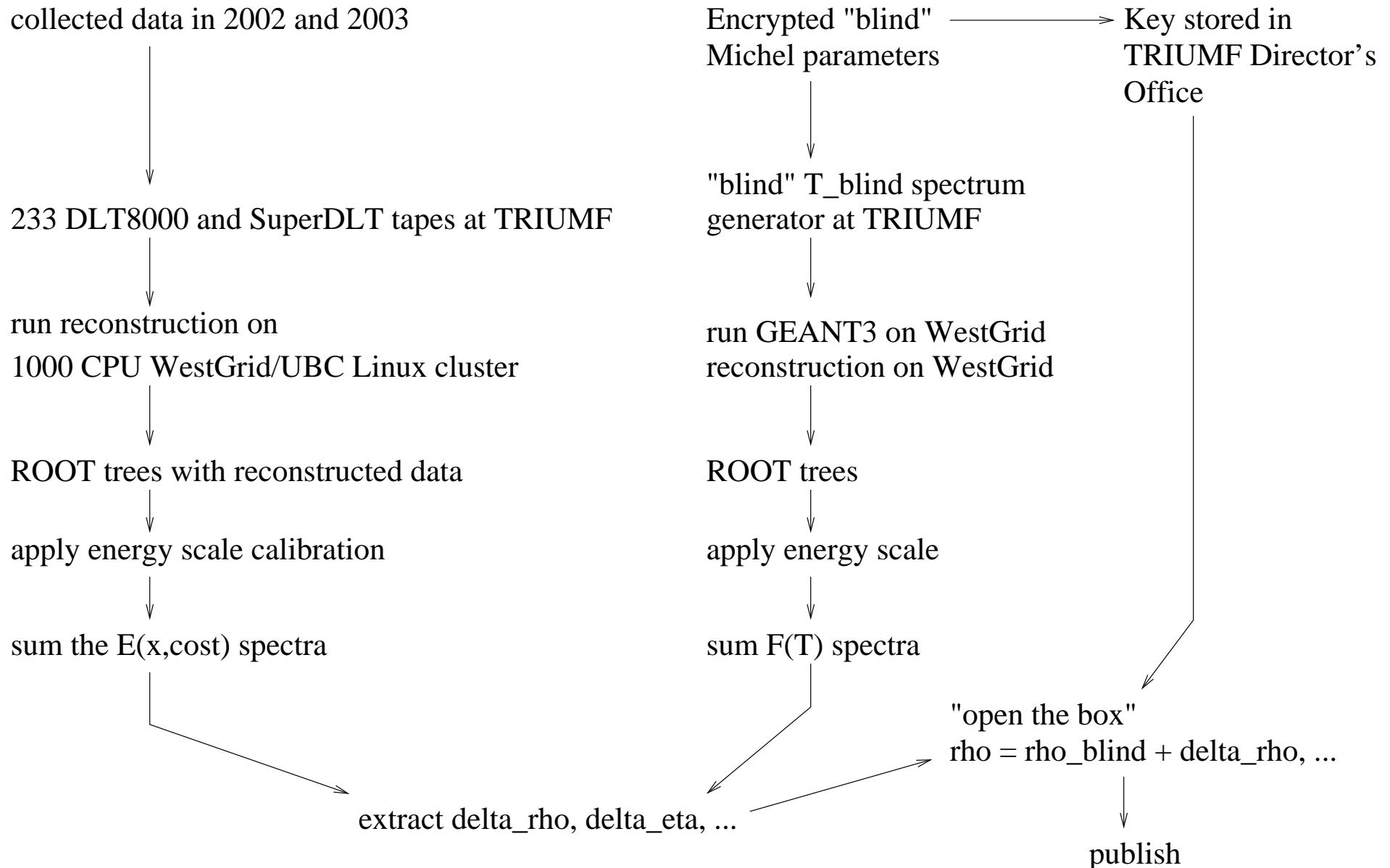
- 2) compare data with data (E_1, E_2) (e.g. measure effect of changing beam rates)

$$E_1 = E_2 + dF/d\rho * \delta_\rho + \dots \quad \longrightarrow \quad \delta_\rho = \text{systematic error due to difference between } E_1 \text{ and } E_2$$

- 3) compare MC with MC (F_1, F_2) (e.g. shadow the data-to-data comparisons for MC verification)

$$F_1(T_{\text{blind}}) = F_2(T_{\text{blind}}) + dF/d\rho * \delta_\rho + \dots \quad \longrightarrow \quad \delta_\rho = \text{systematic error}$$

Data processing on WestGrid



Summary

- have excellent detector – high precision construction, 100% efficient, no noise
- have large data set
- developed fast and efficient event reconstruction program by combining several well known methods
- developed and validated GEANT3 based simulation
- developed blinding technique for extracting Michel parameters
- learned how to efficiently use the 1000 CPU WestGrid/UBC Linux cluster
- presently processing data and geant – main data set and systematics data sets